

Search Notes

Application/Control No.

10/565,740

Examiner

Hien D. Vu

Applicant(s)/Patent under
Reexamination

NEUMETZLER, HEIKO

Art Unit

2833

SEARCHED

Class	Subclass	Date	Examiner
439	404,405, 79,562, 751	7/2/2007	HV
Updated	Search	3/21/2008	HV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR